Notice of References Cited	Application/Control No. 10/705,498	Applicant(s)/Patent Under Reexamination GEORGE ET AL.	
	Examiner Scott L. Jarrett	Art Unit 3623	Page 1 of 4

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,195,041	03-1993	George et al.	700/100
	B	US-5,351,195	09-1994	Sherman, Mark A.	700/100
	C	US-6,633,791	10-2003	Lo et al.	700/101
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Bolch, Gunter, Greiner, Stefan, deMeer, Herman, Trivedi, Kishor, Queueing Networks and Markov Chains John Wiley & Sons, 1998, ISBN: 047119366, Chapters 3, 6, 7 and 13
	V	Koehn, William K., Robust Design Through Design to Six Sigma Manufacturability 1995 Engineering Management Conference, IEEE 1995, Pages 241-246
	W	Rummel, Jeffrey, An empirical investigation of costs in batching decisions Decision Sciences, Volume 31, Number 1, Winter 2000, Pages 79-103
	X	Darlington, Jon, Lean thinking and mass customization: The relapship between product and costs Management Accounting, Volumn 77, Number 10, November 1999, Pages 18-21

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 10/705,498	Applicant(s)/Patent Under Reexamination GEORGE ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Michael, George, Lean Six Sigma: Combining Six Sigma Quality with Lean Speed McGraw-Hill, April 2002, ISBN: 0071385215
	V	Hines, Peter, Rich, Nick, The seven value stream mapping tools International Journal of Operations & Production Management, Volume 17, Issue 1, November 1997
	W	Lee, Hau L., Tang, Christopher S., Modeling the Costs and Benefits of Delayed Product Differentiation Management Science, Volume 43, Issue 1, January 1997, Pages 40-53
	X	Yang, Jiaqin, Deane, Richard H., A lotsize reduction model for just-in-time manufacturing systems Integrated Manufacturing Systems, 2002, Volume 13, Issue 7, Pages 471-488

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 10/705,498	Applicant(s)/Patent Under Reexamination GEORGE ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Bao, Han P., Samarch, J.A., Affordable Design: A methodology to implement process-based manufacturing cost models into the traditional performance-focused multidisciplinary design optimization,American Institue of Aeronautics and Astronautices
	V	Herrmann, Jeffrey, Chincholkar, Mandar M., Design For Production: A tool for reducing manufacturing cycle time Proceedings of DETC 2000, 2000 ASME Design Engineering Technical Conference, Baltimore Maryland
	W	Caramanis, Michael C., Anli, Osman M., Dynamic Lead Time Modeling for JIT Produciton Planning Proccedings of the 1999 IEEE International Conference on Robotics 7 Automation, Detriot Michigan 1999
	X	Caramanis, Michael C., Pan, Haidong, Anli, Osman M., A Closed-Loop Approach to Efficient and Stable Supply-Chain Coordination in Complex Stochastic Manufacturing Systems Proceedings of the American Control Conference, Arlington VA 2001, Pages 1381-1388

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 10/705,498	Applicant(s)/Patent Under Reexamination GEORGE ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Herrmann, Jeffrey W., Chincholkar, Mandar M., Reducing Throughput Time during Product Design Institute for Systems Research, University of Maryland, August 13, 2001, Pages 1-25
	V	Dobson, Gregory, Karmarkar, Uday S., Rummel, Jeffrey L., Batching to Minimize Flow Times on One Machine Management Science, June 1987, Volume 33, Issue 6, Pages 784-799
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.